



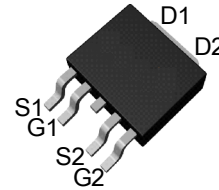
## Features

- N Channel**  
 30V/20A,  
 $R_{DS(ON)} = 14m\Omega$  (typ.) @  $V_{GS} = 10V$   
 $R_{DS(ON)} = 17m\Omega$  (typ.) @  $V_{GS} = 4.5V$
- P Channel**  
 -30V/-20A,  
 $R_{DS(ON)} = 24m\Omega$  (typ.) @  $V_{GS} = -10V$   
 $R_{DS(ON)} = 32m\Omega$  (typ.) @  $V_{GS} = -4.5V$
- 100% UIS +  $R_g$  Tested
- Reliable and Rugged
- Lead Free Available (RoHS Compliant)

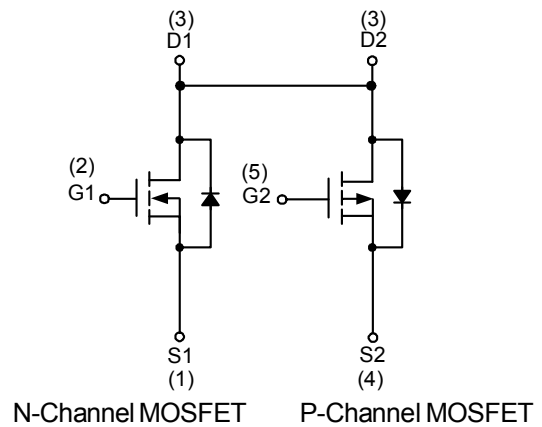
## Applications

- Synchronous Rectification.
- Motor Fan Control.
- High Current, High Speed Switchin.
- H-bridge and Inverter.

## Pin Description



Top View of TO-252-4



## Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX3013	TO-252-4	XPX3013 XXX YYYY	2500

**Absolute Maximum Ratings** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	N Channel	P Channel	Unit	
<b>Common Ratings</b>					
$V_{DSS}$	Drain-Source Voltage	30	-30	V	
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	$\pm 20$	V	
$T_J$	Maximum Junction Temperature	175		$^\circ\text{C}$	
$T_{STG}$	Storage Temperature Range	-55 to 175		$^\circ\text{C}$	
$I_S$	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$	20*	-20	A
$I_{DP}^a$	Pulse Drain Current Tested	$V_{GS}=10\text{V(N)}, V_{GS}=-10\text{V(P)}$	48*	-48*	A
$I_D$	Continuous Drain Current	$T_C=25^\circ\text{C}$	20*	-20*	A
		$T_C=70^\circ\text{C}$	20*	-20*	
$P_D$	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	24	24	W
		$T_C=70^\circ\text{C}$	16	16	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	6.25	6.25	$^\circ\text{C/W}$
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$	20*	-20	A
		$T_A=70^\circ\text{C}$	12*	-9.6	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	7.5	7.5	W
		$T_A=70^\circ\text{C}$	5.25	5.25	
$R_{\theta JA}^b$	Thermal Resistance-Junction to Ambient	$t \leq 10\text{s}$	20	20	$^\circ\text{C/W}$
		Steady State	60	60	
$I_{AS}^c$	Avalanche Current, Single pulse	$L=0.5\text{mH}$	9	-9	A
$E_{AS}^c$	Avalanche Energy, Single pulse	$L=0.5\text{mH}$	20	20	mJ

Note \* : Max. current is limited by bonding wire.

Note a : Pulse width limited by max. junction temperature.

Note b :  $R_{\theta JA}$  steady state  $t=999\text{s}$ .  $R_{\theta JA}$  is measured with the device mounted on  $1\text{in}^2$ , FR-4 board with 2oz. Copper.

Note c : UIS tested and pulse width limited by maximum junction temperature  $175^\circ\text{C}$  (initial temperature  $T_J=25^\circ\text{C}$ ).

**N Channel Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test Conditions	N Channel			Unit
			Min.	Typ.	Max.	
<b>Static Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=24V, V_{GS}=0V$	-	-	1	$\mu A$
		$T_J=85^\circ C$	-	-	30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	1.3	1.8	2.3	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
$R_{DS(ON)}^d$	Drain-Source On-state Resistance	$V_{GS}=10V, I_{DS}=8A$	-	14	18.4	m $\Omega$
		$V_{GS}=4.5V, I_{DS}=5A$	-	17	25	
<b>Diode Characteristics</b>						
$V_{SD}^d$	Diode Forward Voltage	$I_{SD}=1A, V_{GS}=0V$	-	0.75	1.1	V
$t_{rr}$	Reverse Recovery Time	$I_{DS}=8A, dI_{SD}/dt=100A/\mu s$	-	10	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	3.5	-	nC
<b>Dynamic Characteristics</b> <sup>e</sup>						
$R_G$	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$	-	1.7	3.4	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=15V, \text{Frequency}=1.0MHz$	-	545	708	pF
$C_{oss}$	Output Capacitance		-	95	-	
$C_{riss}$	Reverse Transfer Capacitance		-	55	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=15V, R_L=15\Omega, I_{DS}=1A, V_{GEN}=10V, R_G=6\Omega$	-	6	-	ns
$t_r$	Turn-on Rise Time		-	8.6	-	
$t_{d(OFF)}$	Turn-off Delay Time		-	16	-	
$t_f$	Turn-off Fall Time		-	3.6	-	
<b>Gate Charge Characteristics</b> <sup>e</sup>						
$Q_g$	Total Gate Charge	$V_{DS}=15V, V_{GS}=10V, I_{DS}=8A$	-	10.8	16	nC
$Q_g$	Total Gate Charge	$V_{DS}=15V, V_{GS}=4.5V, I_{DS}=8A$	-	5.2	7.8	
$Q_{gth}$	Threshold Gate Charge		-	0.6	-	
$Q_{gs}$	Gate-Source Charge		-	1	-	
$Q_{gd}$	Gate-Drain Charge		-	2.8	-	

Note d : Pulse test ; pulse width $\leq 300\mu s$ , duty cycle $\leq 2\%$ .

Note e : Guaranteed by design, not subject to production testing.

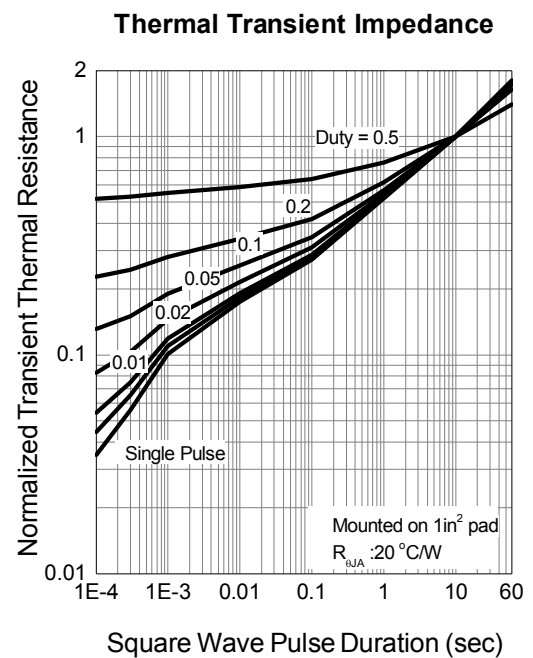
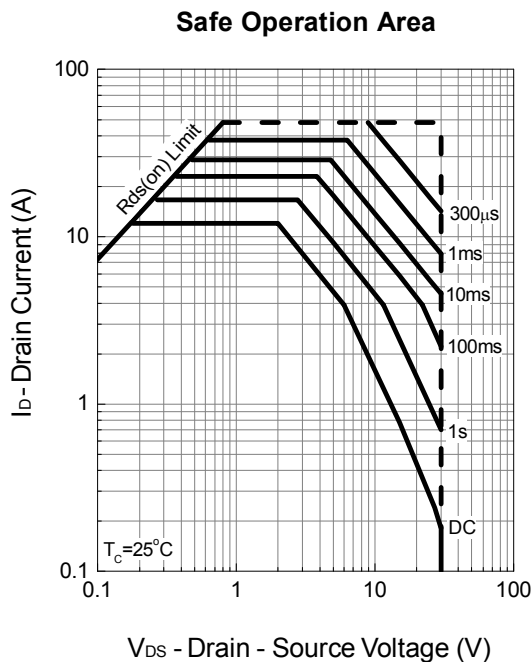
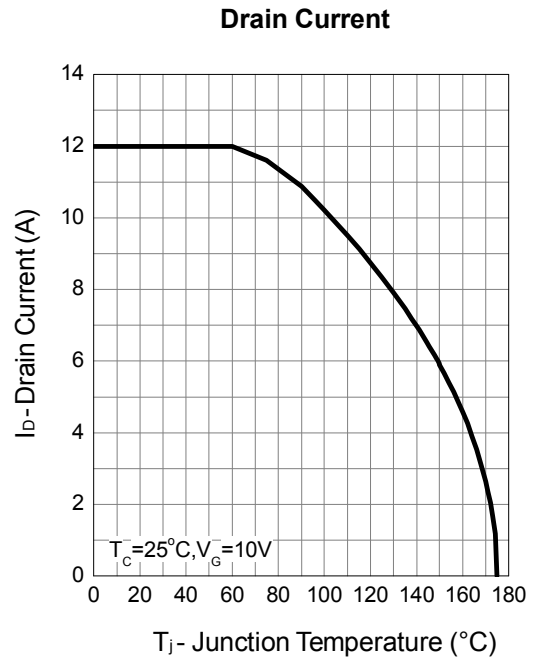
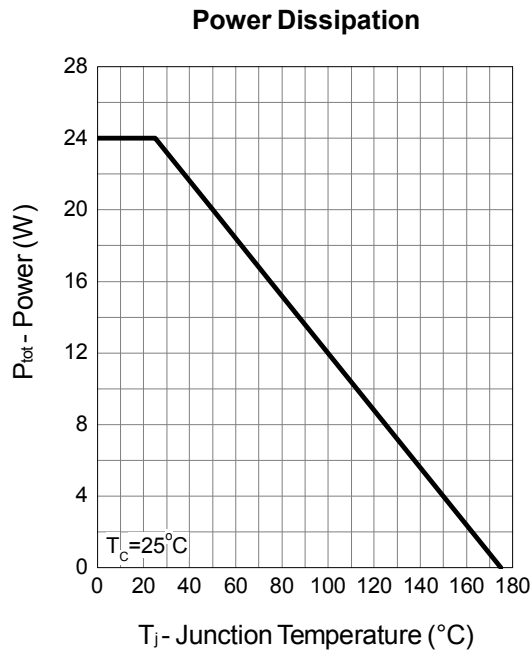
**P Channel Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test Conditions	P Channel			Unit
			Min.	Typ.	Max.	
<b>Static Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=-250\mu A$	-30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-24V, V_{GS}=0V$	-	-	-1	$\mu A$
		$T_J=85^\circ C$	-	-	-30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250\mu A$	-1.3	-1.8	-2.3	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
$R_{DS(ON)}^d$	Drain-Source On-state Resistance	$V_{GS}=-10V, I_{DS}=-12A$	-	24	33.5	m $\Omega$
		$V_{GS}=-4.5V, I_{DS}=-5A$	-	32	44	
<b>Diode Characteristics</b>						
$V_{SD}^d$	Diode Forward Voltage	$I_{SD}=-1A, V_{GS}=0V$	-	-0.75	-1	V
$t_{rr}$	Reverse Recovery Time	$I_{DS}=-12A, di_{SD}/dt=100A/\mu s$	-	11	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	4	-	nC
<b>Dynamic Characteristics<sup>e</sup></b>						
$R_G$	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$	-	3.3	6.6	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=-15V, Frequency=1.0MHz$	-	580	754	$\mu F$
$C_{oss}$	Output Capacitance		-	105	-	
$C_{riss}$	Reverse Transfer Capacitance		-	72	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-15V, R_L=15\Omega, I_{DS}=-1A, V_{GEN}=-10V, R_G=6\Omega$	-	8.7	-	ns
$t_r$	Turn-on Rise Time		-	10	-	
$t_{d(OFF)}$	Turn-off Delay Time		-	22	-	
$t_f$	Turn-off Fall Time		-	9	-	
<b>Gate Charge Characteristics<sup>e</sup></b>						
$Q_g$	Total Gate Charge	$V_{DS}=-15V, V_{GS}=-10V, I_{DS}=-12A$	-	13	-	nC
$Q_{gs}$	Gate-Source Charge		-	1	-	
$Q_{gd}$	Gate-Drain Charge		-	4	-	

Note d : Pulse test; pulse width $\leq 300\mu s$ , duty cycle $\leq 2\%$ .

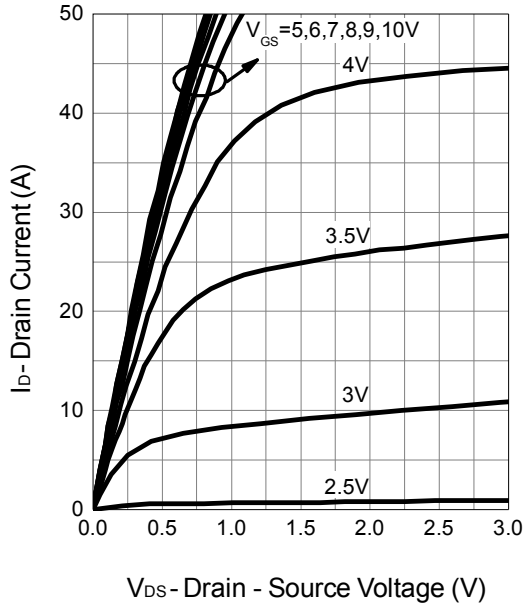
Note e : Guaranteed by design, not subject to production testing.

## N Channel Typical Operating Characteristics

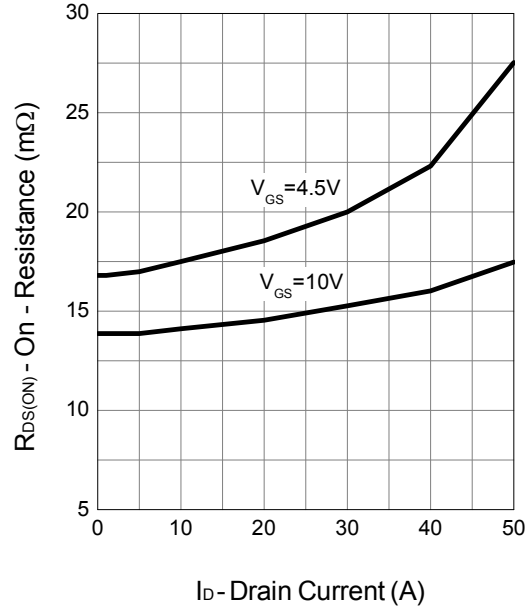


### N Channel Typical Operating Characteristics (Cont.)

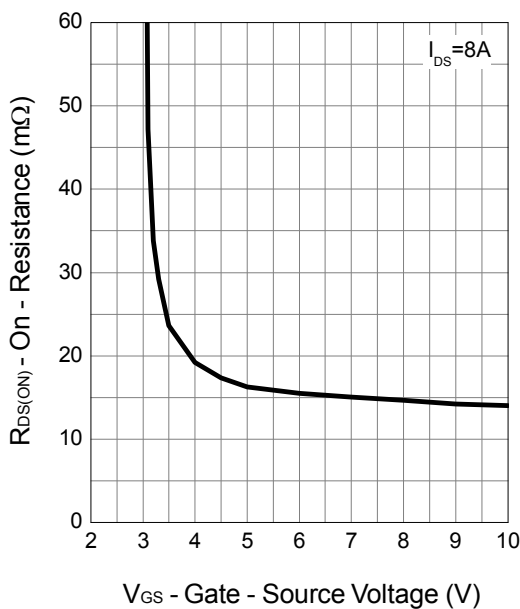
Output Characteristics



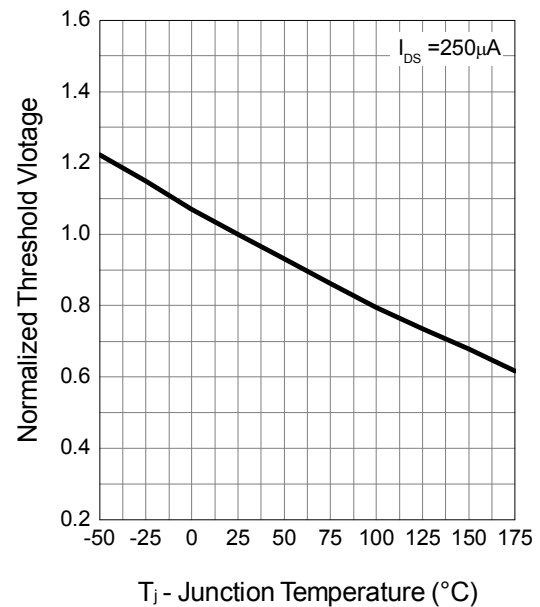
Drain-Source On Resistance



Gate-Source On Resistance

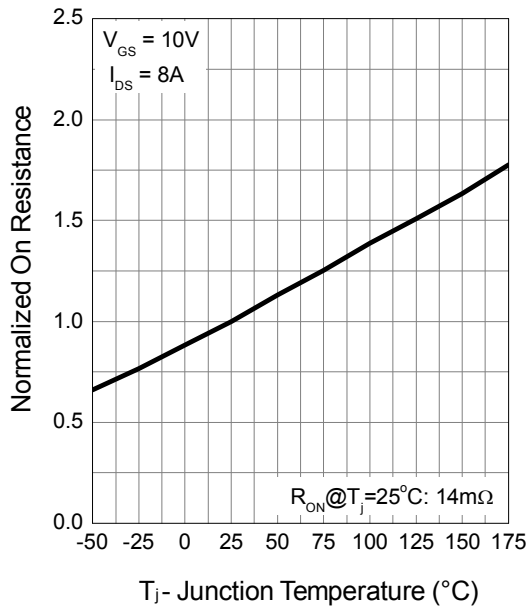


Gate Threshold Voltage

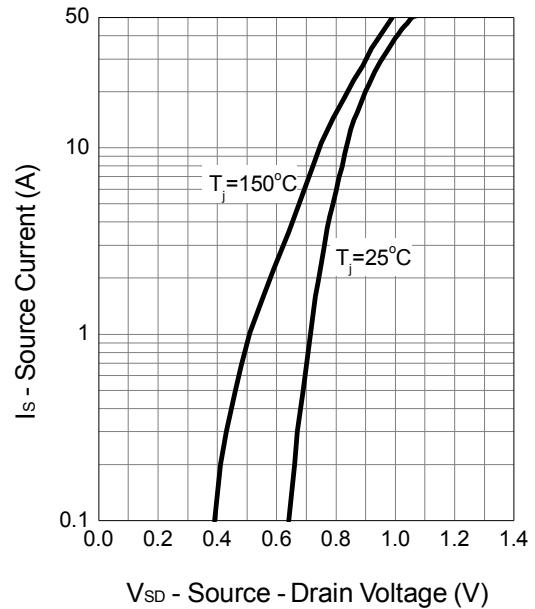


### N Channel Typical Operating Characteristics (Cont.)

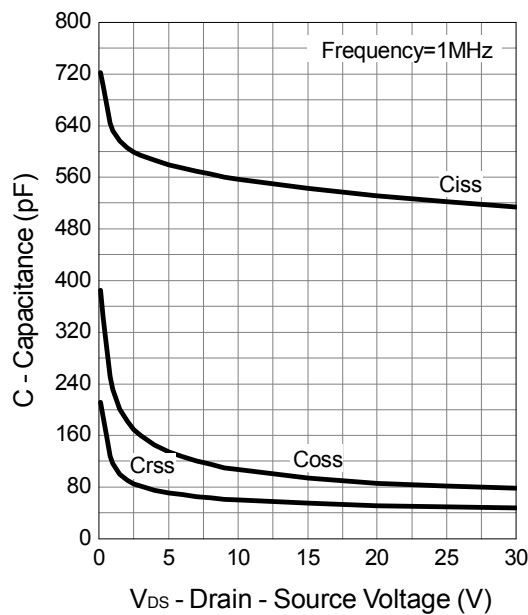
Drain-Source On Resistance



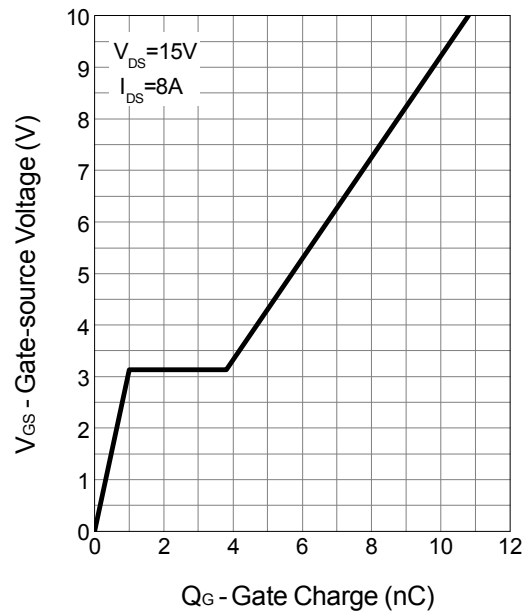
Source-Drain Diode Forward



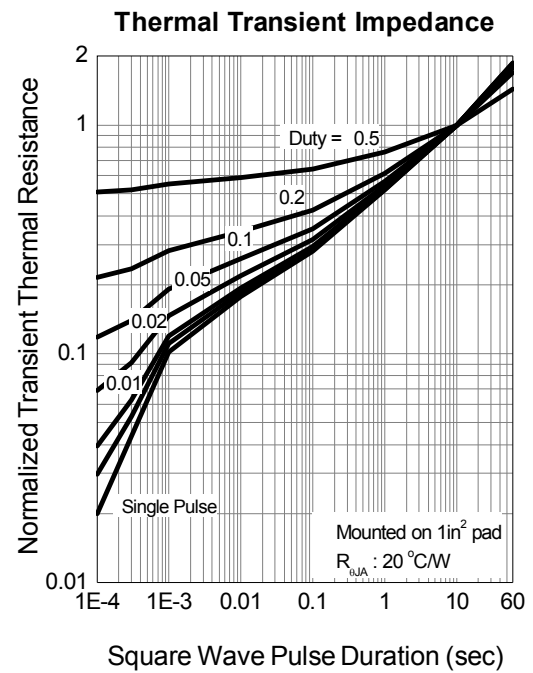
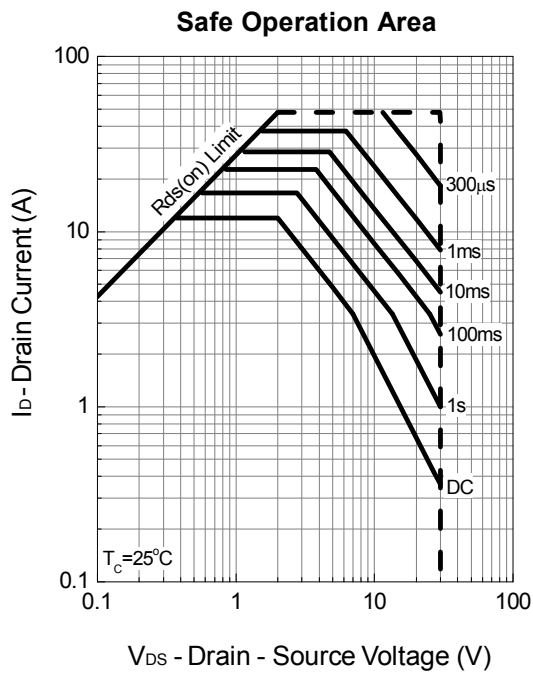
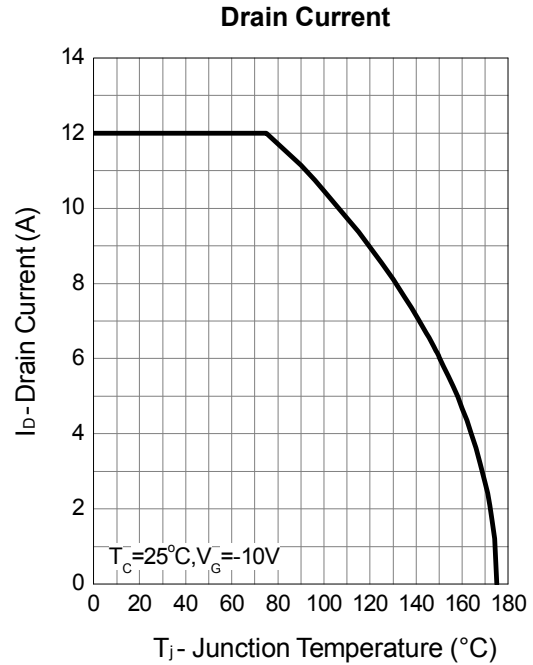
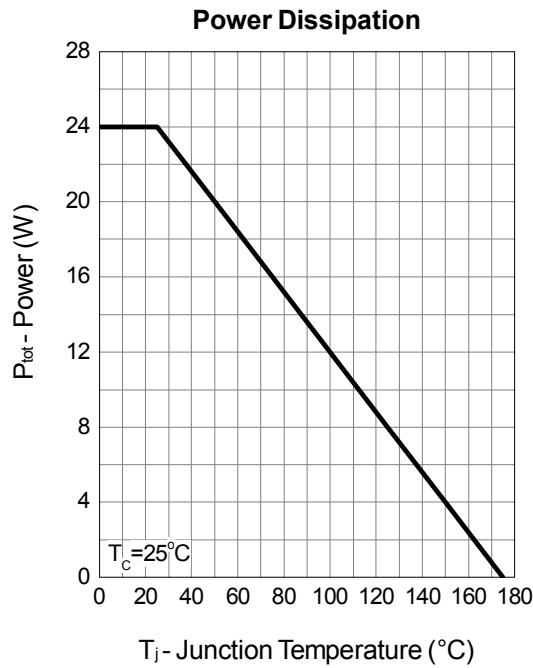
Capacitance



Gate Charge

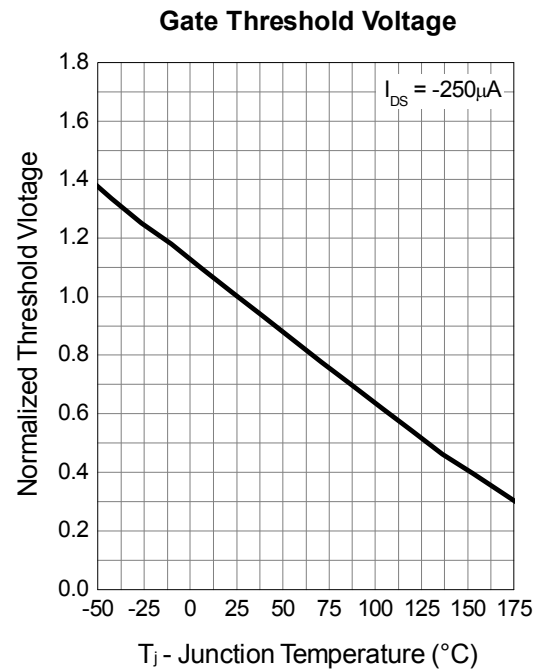
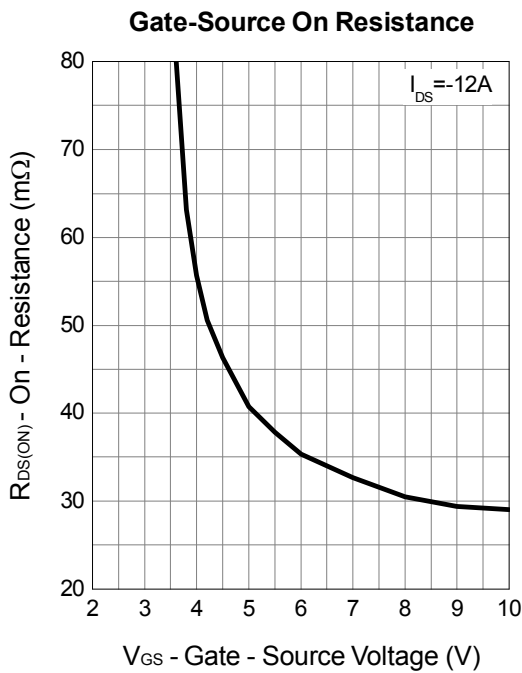
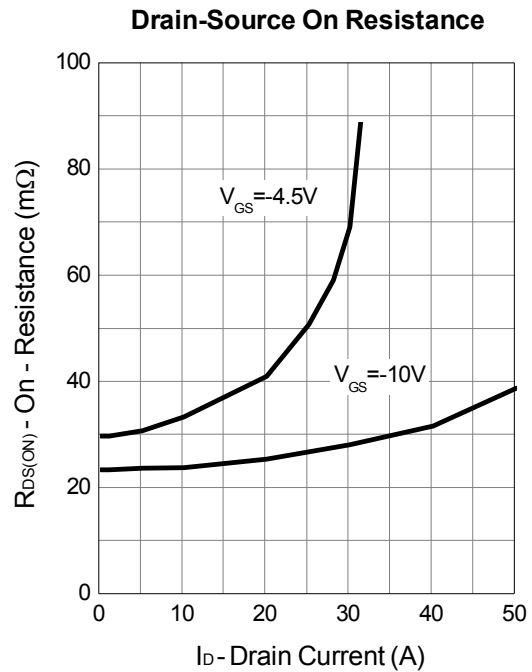
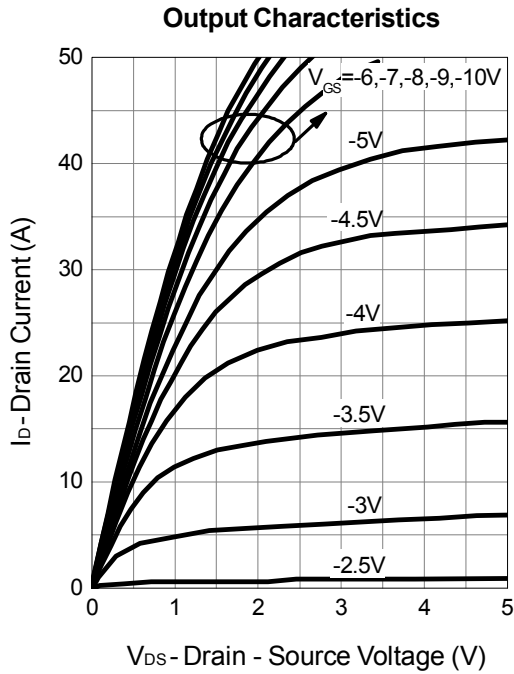


## P Channel Typical Operating Characteristics

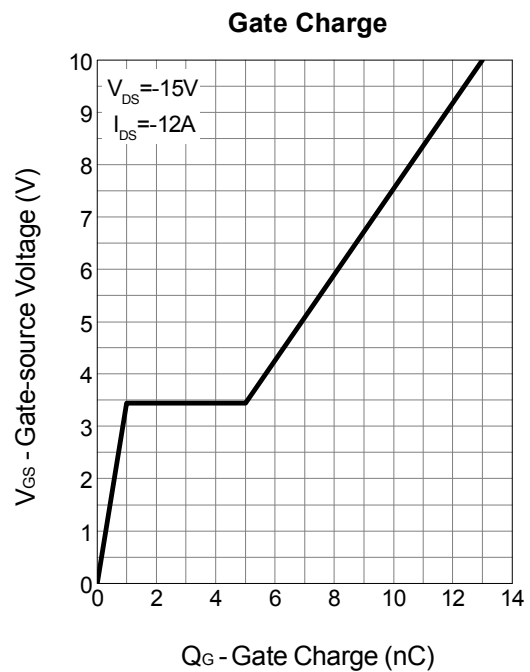
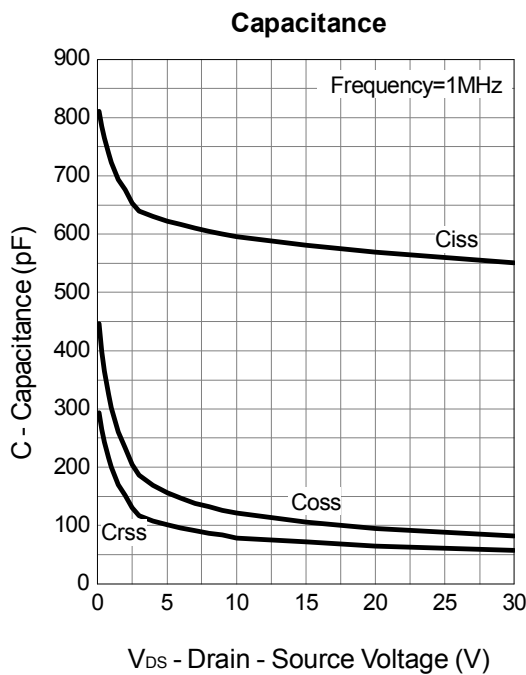
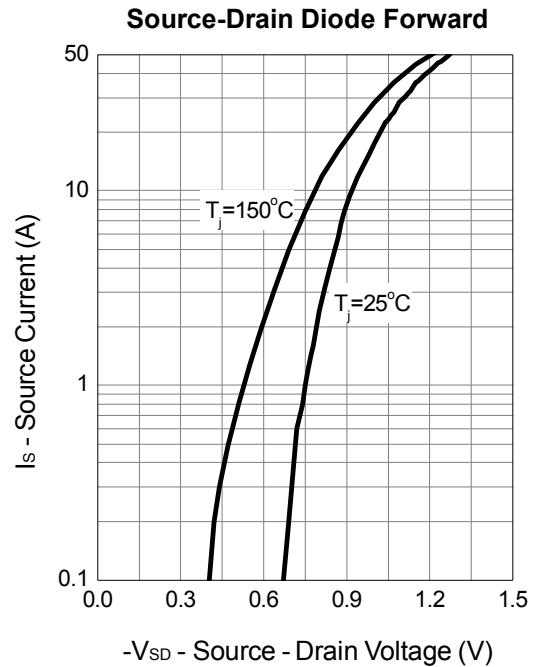
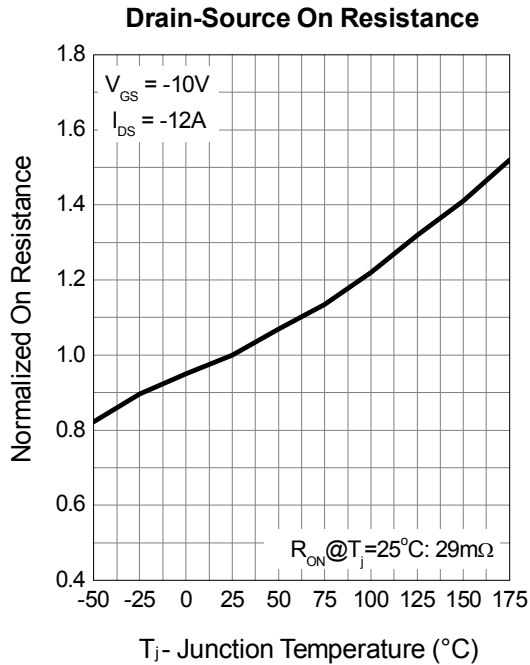




### P Channel Typical Operating Characteristics (Cont.)

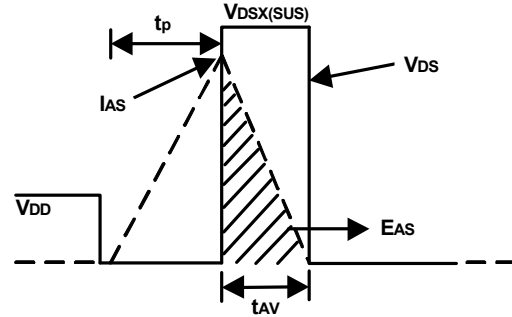
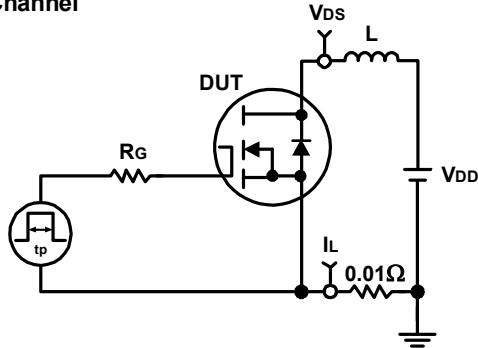


### P Channel Typical Operating Characteristics (Cont.)

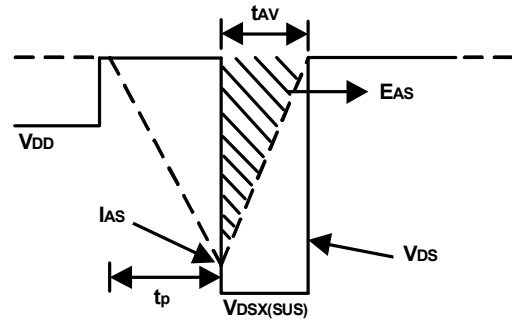
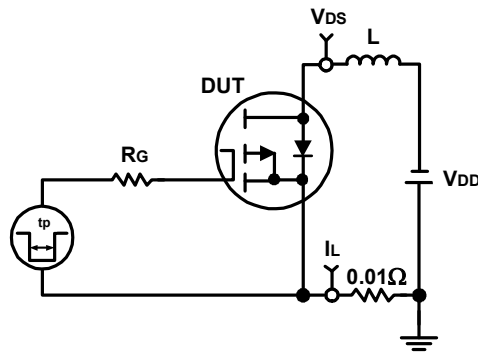


### Avalanche Test Circuit and Waveforms

N Channel

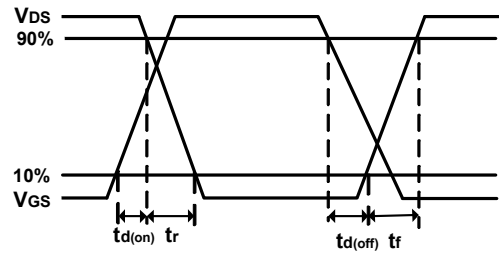
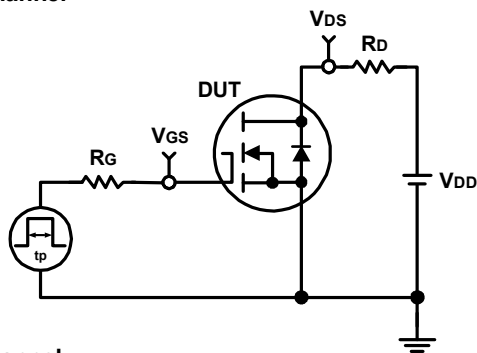


P Channel



### Switching Time Test Circuit and Waveforms

N Channel



P Channel

